

Notice of References Cited	Application/Control No. 10/049,968		Applicant(s)/Patent Under Reexamination WIELAND ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,641,848	11-2003	Bonte et al.	424/757
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Varila et al. British J. Obstetrics and Gynecology (1995) 102: 985-989.
	V	Brincat et al. Maturitas (1987) 9(1): 1-5.
	W	Welzel et al. Tetrahedron (1985) 41(20); 4509-4517.
	X	Affinito et al. Maturitas (1999) 33: 239-247.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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	U	Fujimoto et al. J. Am. Chem. Soc. (1982) 104: 4718-4720.
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